High Performance Analog Products

Tucson Corporation

Analytical Services

Reliability Report For

Qualifying TPS62000YEG in a new package

09/15/2003

Texas Instruments High Performance Analog Products

Approved by:

Mark Yampolsky Supevisor/Reliability Engineering The **TPS62000YEG** is qualified and fully meets the Texas Instruments quality and reliability standards for High Performance Analog Products per the testing described below.

Packaging Information			Manufacturing Information		
Assembly Site:	Unitive/TI-To	icson	Die Name:	BLBD62000C9W	
Package Type:	WCSP/YEG		Die Size:	60 x 86 mils	
Solder Bump Alloy:	63%/37% Tii	n/Lead	Mask Revision:	С	
Solder Bump Diameter:	300µm		Wafer Fab Site:	Dfab	
Bump Pitch:	500μm		Process:	LBC3S (non Cu)	
Number of Solder Bumps:	12		Technology:	LinBiCMOS	
Wafer Coating Material:	LC2850		Metal 1:	TiW/AlCu (2%)	
Redistribution Layer 1:	Electroplated	Copper	Metal 2:	0.3umTiW/ 1.52um AlSiCu (0.5%)	
Flammability Rating	UL94 V-O a	nd	Passivation:	10KA CN	
	IEC Standard	695-2-2			
Moisture Sensitivity Level	1	NA	Transistor Count:	1739	
Reflow Temperature	240°C	N/A			

Thermal Information

Absolute Max Junction Temp T _{J-MAX}	-40°C to +150°C
Recommended Junction Temp T _J	-40°C to +125°C
$ heta_{ m JC}$	21.2°C/W
$ heta_{ m JB}$	N/A
SpecificationOperating Temperature T _A	-65°C to +150°C
Lead SolderingTemperature 1.6mm from case	N/A
Storage Temperature T _{STG}	-65°C to +150°C

Qualification Evaluation & Results:

Qualify TPS62000YEG in Nanostar™ package.

Qualification Material					
HTOL assem/wafer/lot:	0304403/0415602; 0315205/0456001;	Latch Up assem/wafer/lot	0301319/3013939,		
	0315205/0456002	-	3013941,3013942		
HAST assem/wafer/lot:	0304403/0415602; 0315205/0456001;	ESD assem/wafer/lot	0301319/3013939,		
	0315205/0456002		3013941,3013942		
Autoclave assem/wafer/lot:	0304403/0415602; 0315205/0456001;	X-Ray assem/wafer/lot	N/A		
	0315205/0456002	·			
Temp Cycle assem/wafer/lot:	0304403/0415602; 0315205/0456001;	MSL assem/wafer/lot	0304403/0415602;		
	0315205/0456002		0315205/0456001;		
			0315205/0456002		

Qualification by Similarity (QBS):

Reliability data on similar packages and wafer fab processes may be used to support generic qualifications as approved by QRE.

Reliability Test Results:

Test	Conditions	Lot 1 SS/F	Lot 2 SS/F	Lot 3 SS/F	QBS Reference and Results
Life Test	150°C, 300 Hrs.	116/0	116/0	116/0	
HAST	130°C, 85%RH, 33.5 psia, 96 Hrs.	80/0	80/0	80/0	
Autoclave	121°C, 15 psia, 100%RH, 240 Hrs.	80/0	80/0	80/0	
Temp Cycle	-55°C to 125°C, 500 cycles	80/0	79/0	79/0	
BLR Temp Cycle	-40°C to 125°C, 1500 cycles,	36/0			
	5°C/ min Temp Ramp Rate, 12 min dwell				
BLR 3 Point Bend Test	Strain Rate 5 mm/min., 85 mm span	8/0			
BLR Key Push Test	100 cycles/min, 1300μ ^a displacement = 2.7 mm max	8/0			
BLR Drop Test	50 cm	8/0			
ESD	HBM/500 volts	3/0			
	HBM/1000 volts	3/0			
	HBM/1500 volts	3/0			
	HBM/2000 volts	3/0			
	HBM/3000 volts	3/0			
	HBM/4000 volts	3/0			
	CDM/500 volts	3/0			
	CDM/750 volts	3/0			
	CDM/1000 volts	3/0			
	MM/100 volts	3/0			
	MM/200 volts	3/0			
	MM/300 volts	3/0			
Latch Up				6/0	
Elec. Charac. over Temp	PDS	20/0	10/0	10/0	
Physical Dimensions		96/0			
Flammability		15/0			OPA2347YED
Ball Shear		150/0			
Manufacturability		passed			
Hi Temp Storage Life Test		45/0	45/0	45/0	
Hi Temp Storage Life Test		45/0	45/0	45/0	
Moisture Sensitivity	Level 1 @ 240°C	12/0	12/0	12/0	

^{*}Preconditioning bake and humidity soak condition prior to Life test, HAST, Temp Cycle, High Temp Storage Life, and Autoclave: 4 hour bake followed by 24 Hours@ 85°C/85%RH. The shortened bake and humidity soak was based on data from moisture absorption and desorption analysis from this package.

The FIT rate for this device is based upon qualification data from this qualification, process qualification data, and/or ongoing reliability monitoring. Current FIT information is available from the product quality web page.

Reliability Calculations					
MODEL OVEN TEMP C° TEST DEVICES PROCESS	TPS62000YEG 150 348 LBC3S	V		ACTIVATION ENERGY (eV) 0.7 (90% Confidence level)	
	READ POINTS (HOURS)	TOTAL FAILURES	PASS	DEVICE HOURS	
	300	0	348	104400	
	Total Failures	0		104400	
темр.		FAILRATE (FITS)	MTTF (HOURS)		MTTF (YEARS)
25		7.005.00	1 425 : 00		16210.2
25 30		7.00E+00 1.10E+01	1.43E+08 9.11E+07		16310.3 10401.6
35		1.70E+01	5.90E+07		6731.1
40		2.58E+01	3.87E+07		4416.8
45		3.89E+01	2.57E+07		2936.8
50		5.77E+01	1.73E+07		1977.6
55		8.47E+01	1.18E+07		1347.8
60		1.23E+02	8.14E+06		929.3
65		1.76E+02	5.67E+06		647.8
70		2.50E+02	4.00E+06		456.3
75		3.52E+02	2.84E+06		324.7
80		4.89E+02	2.04E+06		233.3
85		6.75E+02	1.48E+06		169.2
90		9.22E+02	1.08E+06		123.8
95		1.25E+03	8.00E+05		91.3
100		1.68E+03	5.95E+05		67.9
105		2.24E+03	4.46E+05		50.9
110		2.97E+03	3.37E+05		38.5
115		3.90E+03	2.56E+05		29.3
120		5.09E+03	1.96E+05		22.4
125		6.60E+03	1.51E+05		17.3

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